# A Unified Uncertainty based Approach for Optimal Quality Decisions

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#### **Problem: Confusion**



For quality we must understand uncertainty But we don't understand how to apply uncertainty to manufacturing... and GUM hasn't been adopted

#### Problem

- Different methods and terms for equivalent quantities
- No single system is fit for purpose
- Arbitrary targets like 'Six-Sigma' are not optimal



#### Accuracy and Uncertainty





#### True value somewhere in this range



Similar terms:

- Error source:
  MSA
- Influence quantity: Uncertainty
- Factor: **SPC**

### Random & Systematic Effects

- Laboratory for Integrated Metrology Applications
- Random effects / Random uncertainty: Uncertainty
- Random error / Precision: MSA
- Common causes: SPC (was chance causes)

Repeatability

(Short-term variability in SPC)

**Reproducibility** (Long-term variability in SPC)



- Bias & Trueness: MSA
- Systematic effects: Uncertainty
  - Caused by Influence quantities
- Special cause variation: SPC
  - Was assignable cause
  - When all compensated, so negligible special cause variation, process is in *Statistical Control:* SPC (was Stable process)



### No single system is fit for purpose







- Gage R&R study often seen as 'truth' in industry
- But reproducibility often limited to part and operator!
- Environmental and material property variations often not represented
- GUM approach forces us to consider effect of all influences

## Laboratory for Integrated Metrology Applications

### SPC can miss systematic effects

- Consider a steel gage measuring a part produced on a steel machine
- Temperature varies
- Expansion of machine and gage cancel
- Significant variation may not appear in SPC data

$$L_{M(T+\Delta T)} = L + \Delta T \ L \ \alpha_M$$

$$L_{P(T)} = L_{M(T+\Delta T)} - \Delta T L \alpha_P$$

$$L_{P(T)} = L + \Delta T L (\alpha_M - \alpha_P)$$

$$L_G = L_{M(T+\Delta T)} - \Delta T \ L \ \alpha_G$$

$$L_G = L + \Delta T L (\alpha_M - \alpha_G)$$

#### **SPC can miss systematic effects**







An uncertainty evaluation (GUM) approach would identify that the gage is not capable, but normally MSA is used which can easily miss this effect.

Limitations of GUM approach

- GUM is 'after-the-fact'
  i.e. correction values
  must already be known
  to evaluate uncertainty
- GUM assumes Gaussian output which is only exact for linear models

 I will use correction for thermal expansion to gives examples of these issues

$$\Delta L = \propto \Delta T \ L_0$$

- Linear assumption is valid
- Typical uncertainties (95%)
  - ∝ : 6% to 10%
  - $-\Delta T$  : 0.1 °C to 0.5 °C
  - *L<sub>0</sub>* : Typically negligible
- Often significant and sometimes dominant





$$\Delta L = \propto \Delta T \ L_0$$

# $u_{\Delta L}^2 \approx (\alpha \, \Delta T \, u_L)^2 + \, (L \, \Delta T \, u_\alpha)^2 + (L \, \alpha \, u_T)^2$

- GUM assumes each input quantity has been determined
- We often need uncertainty before they are determined
  - Estimate uncertainty for a planned measurement
  - Determine probability of parts conforming
- Two approaches typically used
  - If uncertainty in the input has negligible effect use nominal value
  - If it is significant use worst case value
- Why use worst case?
  - Because GUM doesn't have a solution!
- Modelling this is easy if we consider errors and propagate the uncertainty in these errors with MCS

Temp. Correction: GUM Approach



#### $\Delta L = \propto \Delta T \ L_0$

$$\begin{aligned} u_{TE}^{2} &\approx (\alpha \ \Delta T \ u_{L})^{2} + (L \ \Delta T \ u_{\alpha})^{2} + (L \ \alpha \ u_{T})^{2} \\ &+ (\Delta T \ u_{L} \ u_{\alpha})^{2} + (\alpha \ u_{L} \ u_{T})^{2} + (L \ u_{\alpha} \ u_{T})^{2} \\ &+ (u_{T} \ u_{L} \ u_{\alpha})^{2} \end{aligned}$$

- Terms evaluated for 14400 combinations of parameters:
  - Lengths between 1 µm and 100 m
  - Fractional standard uncertainty in length of between 10<sup>-7</sup> and 10<sup>-3</sup>
  - CTE's between 1.2 and 23 ppm/°C
  - Fractional standard uncertainty in CTE of between 0.2% and 37%
  - Temperature offsets of between 0.01 °C and 20 °C
  - Fractional standard uncertainty in measurement of the temperature offset of between 0.001 °C and 2 °C.

Scale Correction: GUM Approach



#### $\Delta L = \propto \Delta T \ L_0$

# $u_{TE}^{2} \approx (\alpha \Delta T u_{L})^{2} + (L \Delta T u_{\alpha})^{2} + (L \alpha u_{T})^{2}$ $+ (\Delta T u_{L} u_{\alpha})^{2} + (\alpha u_{L} u_{T})^{2} + (L u_{\alpha} u_{T})^{2}$ $+ (u_{T} u_{L} u_{\alpha})^{2}$

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Monte Carlo Verification (GUM-S1)





### **Optimize for Cost per Part Sold**



**Fail Verification** 

False Positive, P<sub>3</sub>

True Positive, P2

A part meets 1 of 4 conditions,		Pass Verification
with finite probabilities:	In-Spec'	True Negative, P1
	Out-of-Spec'	False Negative, P4

- Cost of manufacture  $(C_1)$  occurs for every part
- Defects reaching customer have additional cost ( $C_2$ )



- 1. *M* and *P* discreet values (instruments and machines). Try all combo's
- 2. Find *k* to minimize  $C_Q$  for each combination (PS using MVN CDF)



### **Unified Uncertainty**

- Cost based optimization algorithms
  - Process selection
  - Instrument selection
  - Set of conformance limits
- Standardised terminology
- Uncertainty evaluation algorithms
  - Generic models of influences
  - Before-the-fact uncertainty
  - Non-Gaussian distributions
- Algorithms for experimentally verifying uncertainty models





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